



## Description

### JMT N-channel Enhancement Mode Power MOSFET

#### Features

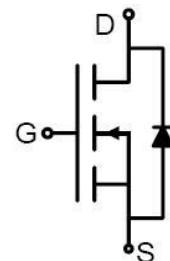
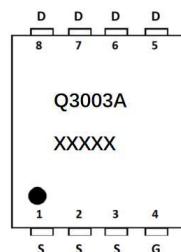
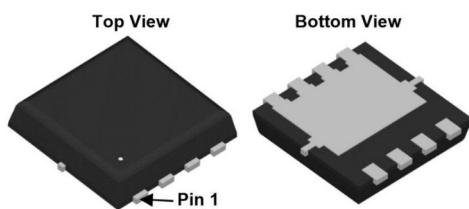
- 30V,80A  
 $R_{DS(ON)} < 3.3\text{m}\Omega$  @  $V_{GS} = 10\text{V}$   
 $R_{DS(ON)} < 6.3\text{m}\Omega$  @  $V_{GS} = 4.5\text{V}$
- Advanced Trench Technology
- Provide Excellent  $R_{DS(ON)}$  and Low Gate Charge
- Lead free product is acquired

#### Application

- Load Switch
- PWM Application
- Power management



100% UIS TESTED!  
100%  $\Delta V_{ds}$  TESTED!



PDFN3x3-8L

Marking and pin Assignment

Schematic Diagram

## Package Marking and Ordering Information

Device Marking	Device	OUTLINE	Device Package	Reel Size	Reel (PCS)	Per Carton (PCS)
Q3003A	JMTQ3003A	TAPING	PDFN3x3-8L	13inch	5000	50000

## Absolute Maximum Ratings ( $T_C=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter		Max.	Units
$V_{DSS}$	Drain-Source Voltage		30	V
$V_{GSS}$	Gate-Source Voltage		$\pm 20$	V
$I_D$	Continuous Drain Current	$T_C = 25^\circ\text{C}$	80	A
		$T_C = 100^\circ\text{C}$	52	A
$I_{DM}$	Pulsed Drain Current <sup>note1</sup>		320	A
$E_{AS}$	Single Pulsed Avalanche Energy <sup>note2</sup>		156	mJ
$P_D$	Power Dissipation	$T_C = 25^\circ\text{C}$	31.7	W
$R_{\theta JC}$	Thermal Resistance, Junction to Case		3.94	$^\circ\text{C}/\text{W}$
$T_J, T_{STG}$	Operating and Storage Temperature Range		-55 to +150	°C

**Electrical Characteristics** ( $T_J=25^\circ\text{C}$  unless otherwise specified)

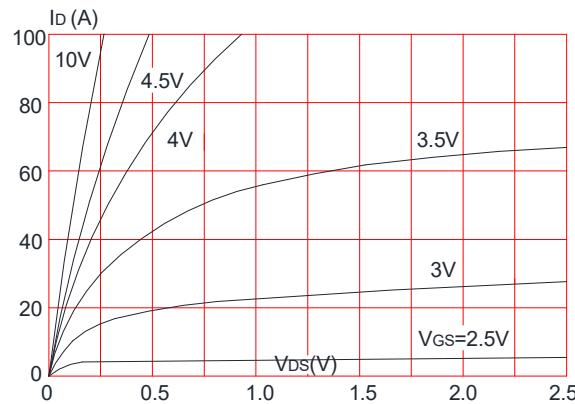
Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
<b>Off Characteristics</b>						
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu\text{A}$	30	-	-	V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=30V, V_{GS}=0V,$	-	-	1.0	$\mu\text{A}$
$I_{GSS}$	Gate to Body Leakage Current	$V_{DS}=0V, V_{GS}=\pm 20V$	-	-	$\pm 100$	nA
<b>On Characteristics</b>						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.0	1.6	2.5	V
$R_{DS(\text{on})}$ note3	Static Drain-Source on-Resistance	$V_{GS}=10V, I_D=30A$	-	2.5	3.3	$\text{m}\Omega$
		$V_{GS}=4.5V, I_D=20A$	-	4.5	6.3	
<b>Dynamic Characteristics</b>						
$C_{iss}$	Input Capacitance	$V_{DS}=15V, V_{GS}=0V, f=1.0\text{MHz}$	-	3500	-	pF
$C_{oss}$	Output Capacitance		-	500	-	pF
$C_{rss}$	Reverse Transfer Capacitance		-	431	-	pF
$Q_g$	Total Gate Charge	$V_{DS}=15V, I_D=30A, V_{GS}=10V$	-	70	-	nC
$Q_{gs}$	Gate-Source Charge		-	11	-	nC
$Q_{gd}$	Gate-Drain("Miller") Charge		-	18	-	nC
<b>Switching Characteristics</b>						
$t_{d(on)}$	Turn-on Delay Time	$V_{DS}=15V, I_D=30A, R_{GEN}=3\Omega, V_{GS}=10V$	-	13	-	ns
$t_r$	Turn-on Rise Time		-	120	-	ns
$t_{d(off)}$	Turn-off Delay Time		-	60	-	ns
$t_f$	Turn-off Fall Time		-	110	-	ns
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
$I_s$	Maximum Continuous Drain to Source Diode Forward Current	-	-	80	A	
$I_{SM}$	Maximum Pulsed Drain to Source Diode Forward Current	-	-	320	A	
$V_{SD}$	Drain to Source Diode Forward Voltage	$V_{GS}=0V, I_s=30A$	-	-	1.2	V
$trr$	Body Diode Reverse Recovery Time	$I_F=20A, dI/dt=100A/\mu\text{s}$	-	21	-	ns
$Qrr$	Body Diode Reverse Recovery Charge		-	9	-	nC

Notes: 1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

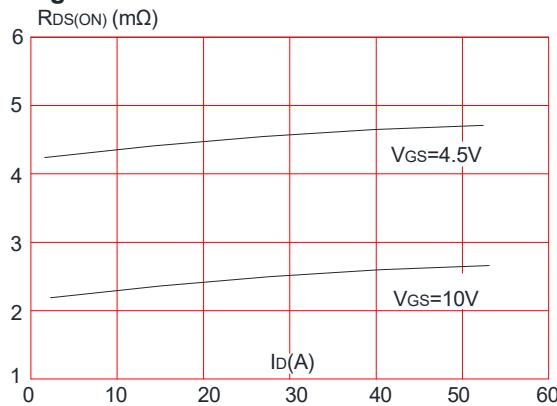
2. EAS condition:  $T_J=25^\circ\text{C}$ ,  $V_{DD}=15V$ ,  $V_G=10V$ ,  $R_G=25\Omega$ ,  $L=0.5\text{mH}$ ,  $I_{AS}=25A$ 3. Pulse Test: Pulse Width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 0.5\%$

## Typical Performance Characteristics

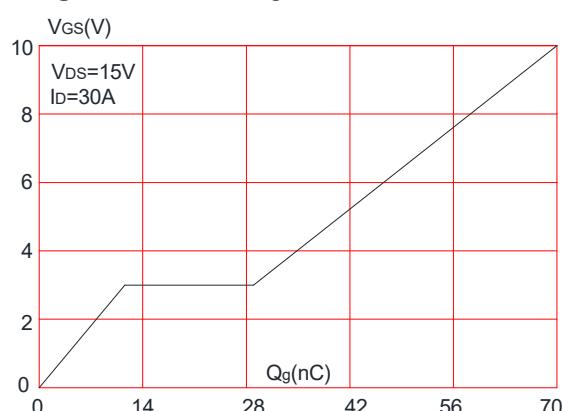
**Figure 1:** Output Characteristics



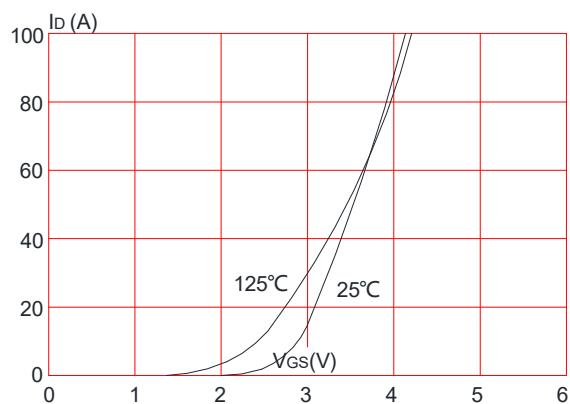
**Figure 3:** On-resistance vs. Drain Current



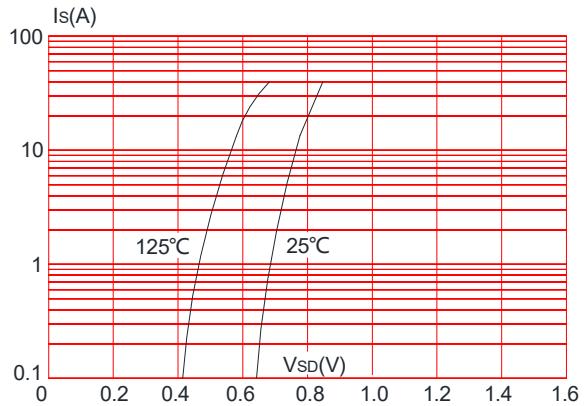
**Figure 5:** Gate Charge Characteristics



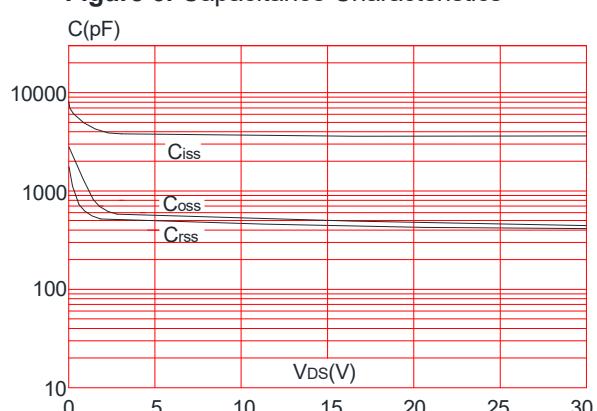
**Figure 2:** Typical Transfer Characteristics



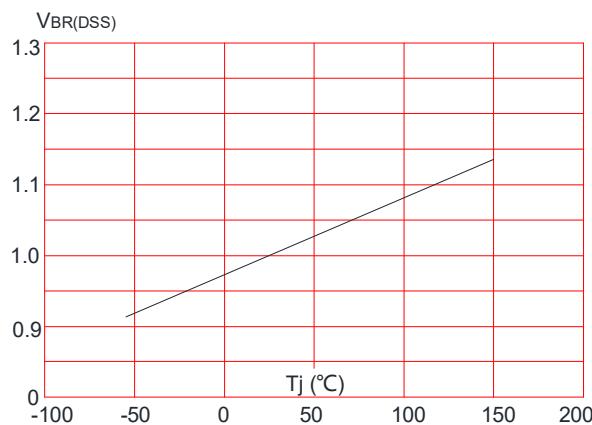
**Figure 4:** Body Diode Characteristics



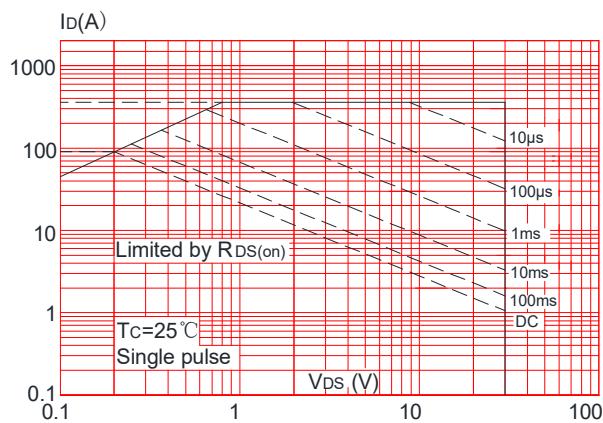
**Figure 6:** Capacitance Characteristics



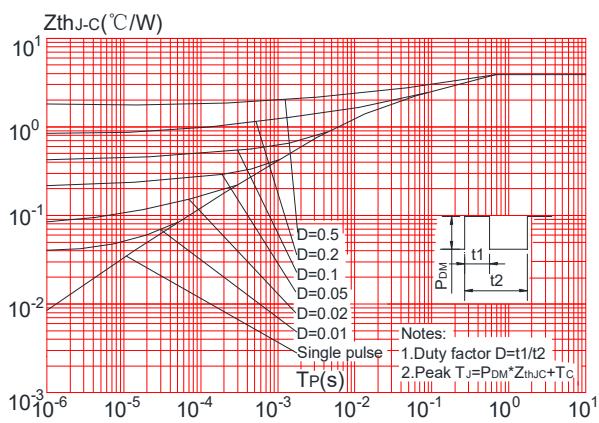
**Figure 7:** Normalized Breakdown Voltage vs. Junction Temperature



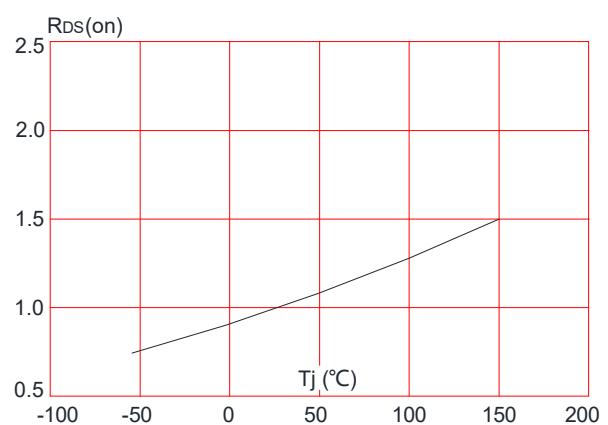
**Figure 9:** Maximum Safe Operating Area



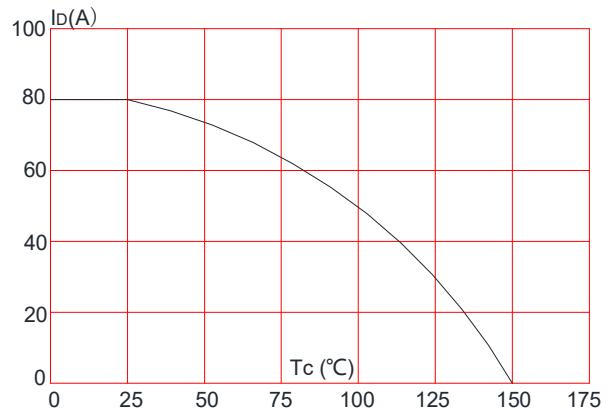
**Figure 11:** Maximum Effective Transient Thermal Impedance, Junction-to-Case



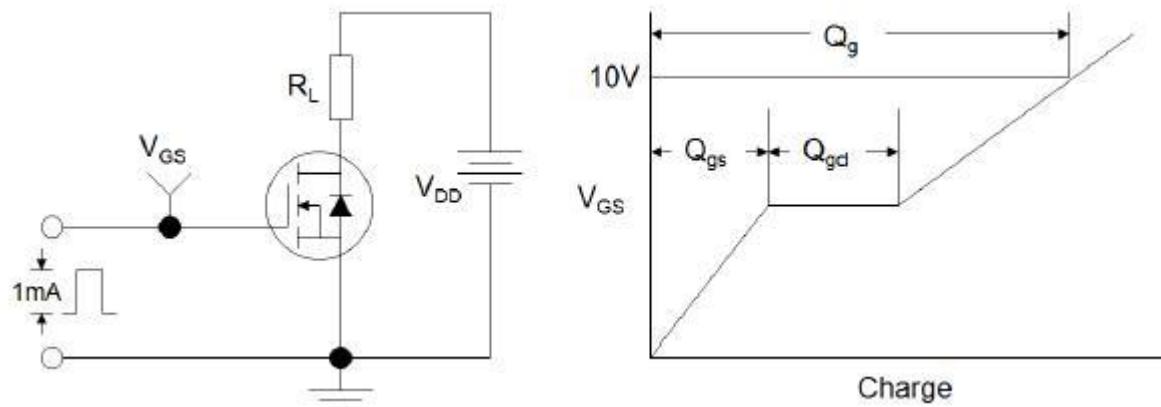
**Figure 8:** Normalized on Resistance vs. Junction Temperature



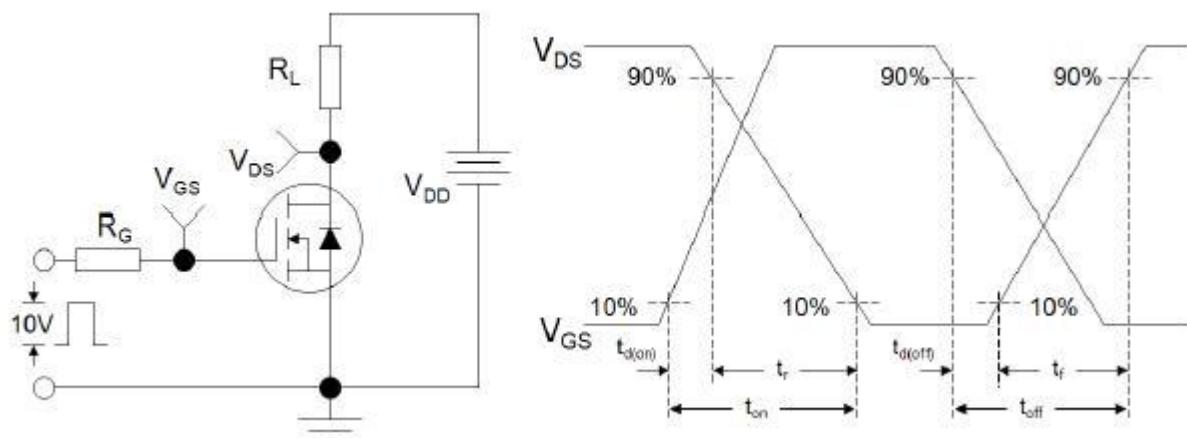
**Figure 10:** Maximum Continuous Drain Current vs. Case Temperature



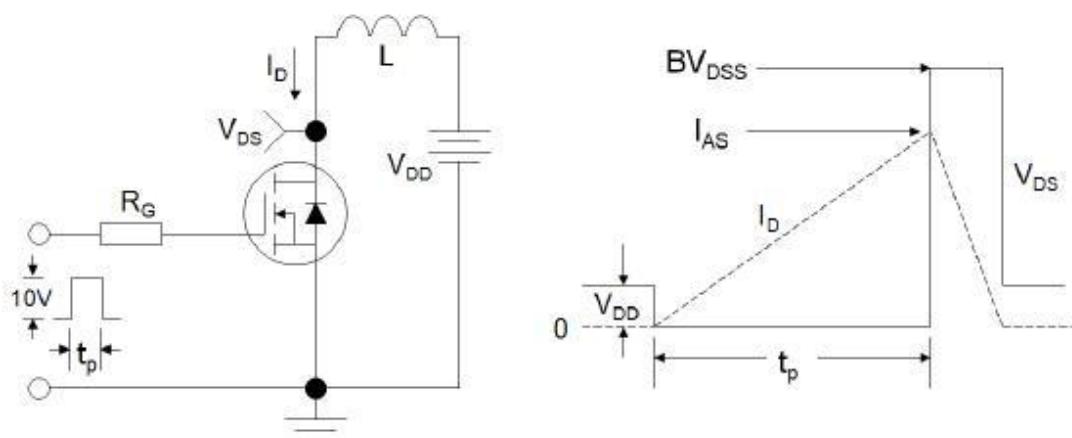
## Test Circuit



**Figure1:Gate Charge Test Circuit & Waveform**



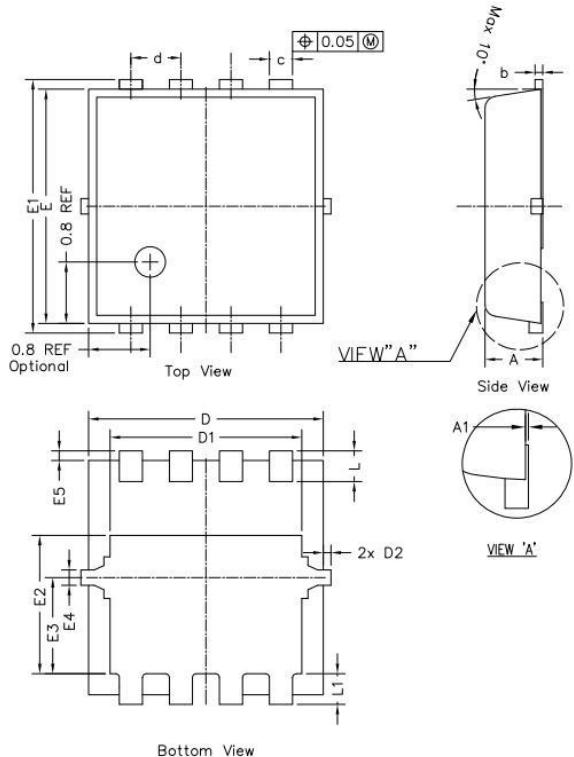
**Figure 2: Resistive Switching Test Circuit & Waveforms**



**Figure 3:Unclamped Inductive Switching Test Circuit & Waveforms**



## Package Mechanical Data-PDFN3x3-8L



SYMBOLS	DIMENSION IN MM			DIMENSION IN INCHES		
	MIN	NOM	MAX	MIN	NOM	MAX
A	0.700	0.750	0.800	0.028	0.030	0.031
A1	---	---	0.050	----	----	0.002
b	0.144	0.152	0.202	0.006	0.006	0.008
c	0.250	0.300	0.350	0.010	0.012	0.014
d	0.65 BSC			0.026 BSC		
D	2.950	3.050	3.150	0.116	0.120	0.124
D1	2.390	2.490	2.590	0.094	0.098	0.102
D2	---	---	0.125	---	---	0.005
E	2.950	3.050	3.150	0.116	0.120	0.124
E1	3.200	3.300	3.400	0.126	0.130	0.134
E2	1.700	1.800	1.900	0.067	0.071	0.075
E3	1.150	1.250	1.350	0.045	0.049	0.053
E4	0.150	0.200	0.250	0.006	0.008	0.010
E5	0.075	0.125	0.175	0.003	0.005	0.007
L	0.300	0.400	0.500	0.01	0.02	0.02
L1	0.300	0.400	0.500	0.01	0.02	0.02

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